

## 2Mb Ultra-Low Power Asynchronous CMOS SRAM 256K × 8 bit

#### Overview

The N02L83W2A is an integrated memory device containing a 2 Mbit Static Random Access Memory organized as 262,144 words by 8 bits. The device is designed and fabricated using ON Semiconductor's advanced CMOS technology to provide both high-speed performance and ultra-low power. The device operates with two chip enable (CE1 and CE2) controls and output enable (OE) to allow for easy memory expansion. The N02L83W2A is optimal for various applications where low-power is critical such as battery backup and hand-held devices. The device can operate over a very wide temperature range of -40°C to +85°C and is available in JEDEC standard packages compatible with other standard 256Kb x 8 SRAMs

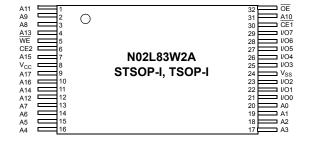
#### **Features**

- Single Wide Power Supply Range 2.3 to 3.6 Volts
- Very low standby current 2.0µA at 3.0V (Typical)
- Very low operating current
   2.0mA at 3.0V and 1µs (Typical)
- Very low Page Mode operating current 0.8mA at 3.0V and 1µs (Typical)
- Simple memory control
   Dual Chip Enables (CE1 and CE2)
   Output Enable (OE) for memory expansion
- Low voltage data retention
   Vcc = 1.8V
- Very fast output enable access time 30ns OE access time
- · Automatic power down to standby mode
- TTL compatible three-state output driver

### **Product Family**

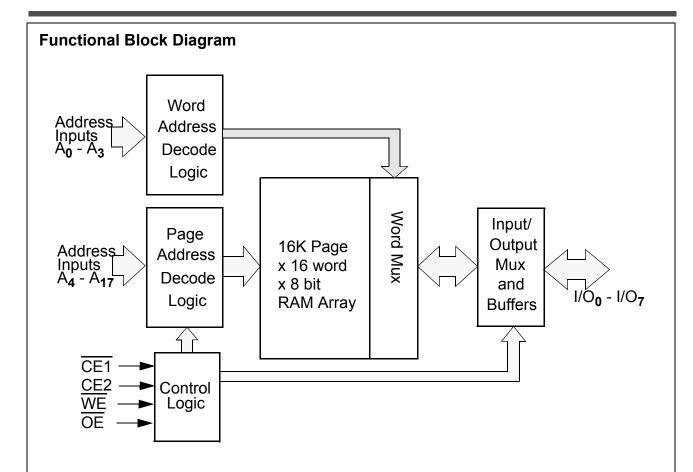
Part Number	Package Type	Operating Temperature	Power Supply (Vcc)	Speed	Standby Current (I <sub>SB</sub> ), Typical	Operating Current (Icc), Typical	
N02L83W2AT	32 - TSOP I						
N02L83W2AN	32 - STSOP I	-40°C to +85°C	-40°C to +85°C	2 2 1/ 2 6 1/	55ns @ 2.7V	2 4	2 1 1 1
N02L83W2AT2	32 - TSOP I Green			2.30 - 3.00	70ns @ 2.3V	2 μΑ	2 mA @ 1MHz
N02L83W2AN2	32 - STSOP I Green						

### **Pin Configuration**



### **Pin Descriptions**

Pin Name	Pin Function	
A <sub>0</sub> -A <sub>17</sub>	Address Inputs	
WE	Write Enable Input	
CE1, CE2	Chip Enable Input	
ŌĒ	Output Enable Input	
I/O <sub>0</sub> -I/O <sub>7</sub>	Data Inputs/Outputs	
V <sub>CC</sub>	Power	
$V_{SS}$	Ground	



### **Functional Description**

CE1	CE2	WE	OE	I/O <sub>0</sub> - I/O <sub>7</sub>	MODE	POWER
Н	Х	X	X	High Z	Standby <sup>1</sup>	Standby
Х	L	Х	Х	High Z	Standby <sup>1</sup>	Standby
L	Н	L	$X^2$	Data In	Write <sup>2</sup>	Active
L	Н	Н	L	Data Out	Read	Active
L	Н	Н	Н	High Z	Active	Active

<sup>1.</sup> When the device is in standby mode, control inputs ( $\overline{\text{WE}}$  and  $\overline{\text{OE}}$ ), address inputs and data input/outputs are internally isolated from any external influence and disabled from exerting any influence externally.

### Capacitance<sup>1</sup>

Item	Symbol	Test Condition	Min	Max	Unit
Input Capacitance	C <sub>IN</sub>	V <sub>IN</sub> = 0V, f = 1 MHz, T <sub>A</sub> = 25°C		8	pF
I/O Capacitance	C <sub>I/O</sub>	V <sub>IN</sub> = 0V, f = 1 MHz, T <sub>A</sub> = 25°C		8	pF

<sup>1.</sup> These parameters are verified in device characterization and are not 100% tested

<sup>2.</sup> When  $\overline{\text{WE}}$  is invoked, the  $\overline{\text{OE}}$  input is internally disabled and has no effect on the circuit.

### Absolute Maximum Ratings<sup>1</sup>

Item	Symbol	Rating	Unit
Voltage on any pin relative to V <sub>SS</sub>	V <sub>IN,OUT</sub>	-0.3 to V <sub>CC</sub> +0.3	V
Voltage on $V_{CC}$ Supply Relative to $V_{SS}$	V <sub>CC</sub>	-0.3 to 4.5	V
Power Dissipation	$P_{D}$	500	mW
Storage Temperature	T <sub>STG</sub>	-40 to 125	°C
Operating Temperature	T <sub>A</sub>	-40 to +85	°C
Soldering Temperature and Time	T <sub>SOLDER</sub>	260°C, 10sec	°C

<sup>1.</sup> Stresses greater than those listed above may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operating section of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

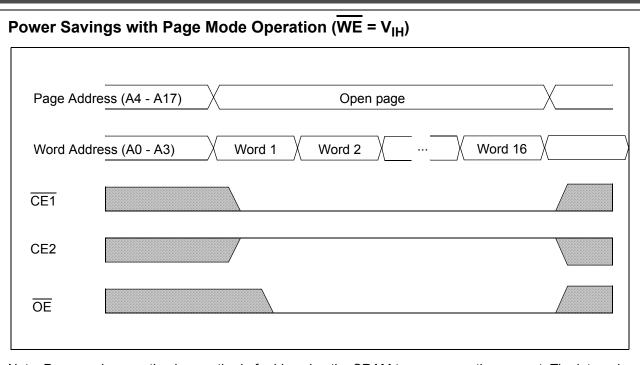
### **Operating Characteristics (Over Specified Temperature Range)**

Item	Symbol	Test Conditions	Min.	Typ <sup>1</sup>	Max	Unit
Supply Voltage	V <sub>CC</sub>		2.3	3.0	3.6	V
Data Retention Voltage	$V_{DR}$	Chip Disabled <sup>3</sup>	1.8			V
Input High Voltage	V <sub>IH</sub>		1.8		V <sub>CC</sub> +0.3	V
Input Low Voltage	V <sub>IL</sub>		-0.3		0.6	V
Output High Voltage	V <sub>OH</sub>	I <sub>OH</sub> = 0.2mA	V <sub>CC</sub> -0.2			V
Output Low Voltage	V <sub>OL</sub>	I <sub>OL</sub> = -0.2mA			0.2	V
Input Leakage Current	I <sub>LI</sub>	$V_{IN}$ = 0 to $V_{CC}$			0.5	μА
Output Leakage Current	I <sub>LO</sub>	OE = V <sub>IH</sub> or Chip Disabled			0.5	μА
Read/Write Operating Supply Current @ 1 µs Cycle Time <sup>2</sup>	I <sub>CC1</sub>	$V_{CC}$ =3.6 V, $V_{IN}$ = $V_{IH}$ or $V_{IL}$ Chip Enabled, $I_{OUT}$ = 0		2.0	4.0	mA
Read/Write Operating Supply Current  @ 70 ns Cycle Time <sup>2</sup>	I <sub>CC2</sub>	$V_{CC}$ =3.6 V, $V_{IN}$ = $V_{IH}$ or $V_{IL}$ Chip Enabled, $I_{OUT}$ = 0		12.0	16.0	mA
Page Mode Operating Supply Current @ 70 ns Cycle Time <sup>2</sup> (Refer to Power Savings with Page Mode Operation diagram)	I <sub>CC3</sub>	$V_{CC}$ =3.6 V, $V_{IN}$ = $V_{IH}$ or $V_{IL}$ Chip Enabled, $I_{OUT}$ = 0		4.0		mA
Read/Write Quiescent Operating Supply Current <sup>3</sup>	I <sub>CC4</sub>	$V_{CC}$ =3.6 V, $V_{IN}$ = $V_{IH}$ or $V_{IL}$ Chip Enabled, $I_{OUT}$ = 0, f = 0			3.0	mA
Maximum Standby Current <sup>3</sup>	I <sub>SB1</sub>	$V_{IN} = V_{CC}$ or 0V Chip Disabled $t_A = 85^{\circ}C$ , $V_{CC} = 3.6$ V		2.0	20.0	μА
Maximum Data Retention Current <sup>3</sup>	I <sub>DR</sub>	$V_{CC}$ = 1.8V, $V_{IN}$ = $V_{CC}$ or 0 Chip Disabled, $t_A$ = 85°C			10.0	μА

<sup>1.</sup> Typical values are measured at Vcc=Vcc Typ., T<sub>A</sub>=25°C and not 100% tested.

<sup>2.</sup> This parameter is specified with the outputs disabled to avoid external loading effects. The user must add current required to drive output capacitance expected in the actual system.

<sup>3.</sup> This device assumes a standby mode if the chip is disabled ( $\overline{\text{CE1}}$  high or CE2 low). In order to achieve low standby current all inputs must be within 0.2 volts of either VCC or VSS.



Note: Page mode operation is a method of addressing the SRAM to save operating current. The internal organization of the SRAM is optimized to allow this unique operating mode to be used as a valuable power saving feature.

The only thing that needs to be done is to address the SRAM in a manner that the internal page is left open and 8-bit words of data are read from the open page. By treating addresses A0-A3 as the least significant bits and addressing the 16 words within the open page, power is reduced to the page mode value which is considerably lower than standard operating currents for low power SRAMs.

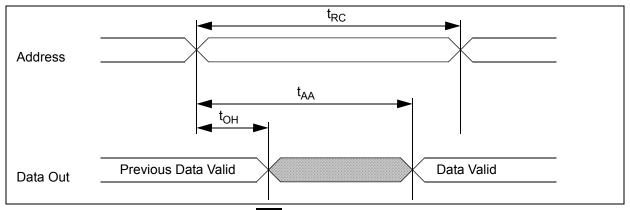
## **Timing Test Conditions**

Item	
Input Pulse Level	$0.1 V_{CC}$ to $0.9 V_{CC}$
Input Rise and Fall Time	5ns
Input and Output Timing Reference Levels	0.5 V <sub>CC</sub>
Output Load	CL = 30pF
Operating Temperature	-40 to +85 °C

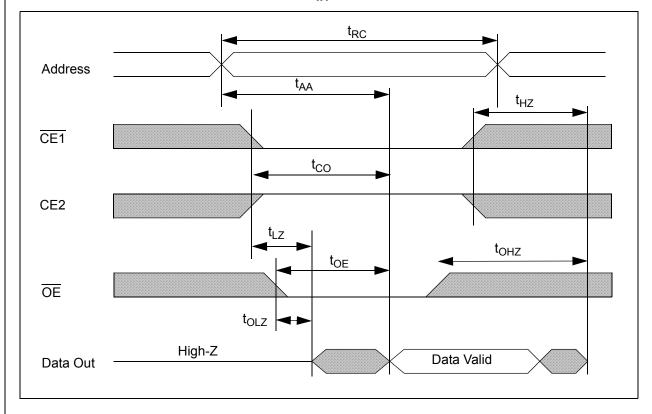
### **Timing**

14	0	2.3 -	3.6 V	V 2.7 - 3.6 V		Heite
Item	Symbol	Min.	Max.	Min.	Max.	Units
Read Cycle Time	t <sub>RC</sub>	70		55		ns
Address Access Time	t <sub>AA</sub>		70		55	ns
Chip Enable to Valid Output	t <sub>co</sub>		70		55	ns
Output Enable to Valid Output	t <sub>OE</sub>		35		30	ns
Chip Enable to Low-Z output	t <sub>LZ</sub>	10		10		ns
Output Enable to Low-Z Output	t <sub>OLZ</sub>	5		5		ns
Chip Disable to High-Z Output	t <sub>HZ</sub>	0	20	0	15	ns
Output Disable to High-Z Output	t <sub>OHZ</sub>	0	20	0	15	ns
Output Hold from Address Change	t <sub>ОН</sub>	10		10		ns
Write Cycle Time	t <sub>WC</sub>	70		55		ns
Chip Enable to End of Write	t <sub>CW</sub>	50		45		ns
Address Valid to End of Write	t <sub>AW</sub>	50		45		ns
Write Pulse Width	t <sub>WP</sub>	40		35		ns
Address Setup Time	t <sub>AS</sub>	0		0		ns
Write Recovery Time	t <sub>WR</sub>	0		0		ns
Write to High-Z Output	t <sub>WHZ</sub>		20		15	ns
Data to Write Time Overlap	t <sub>DW</sub>	40		35		ns
Data Hold from Write Time	t <sub>DH</sub>	0		0		ns
End Write to Low-Z Output	t <sub>OW</sub>	5		5		ns

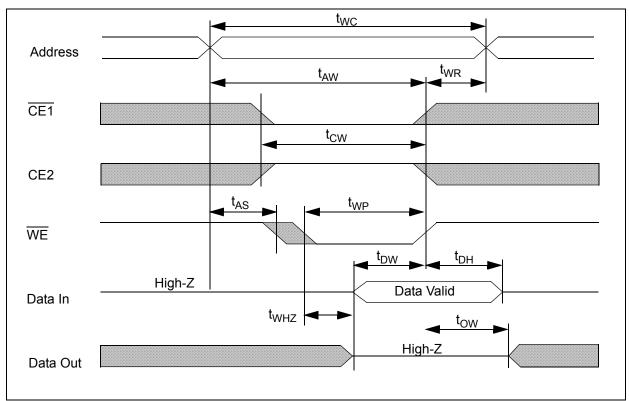
## Timing of Read Cycle ( $\overline{CE1} = \overline{OE} = V_{IL}$ , $\overline{WE} = CE2 = V_{IH}$ )



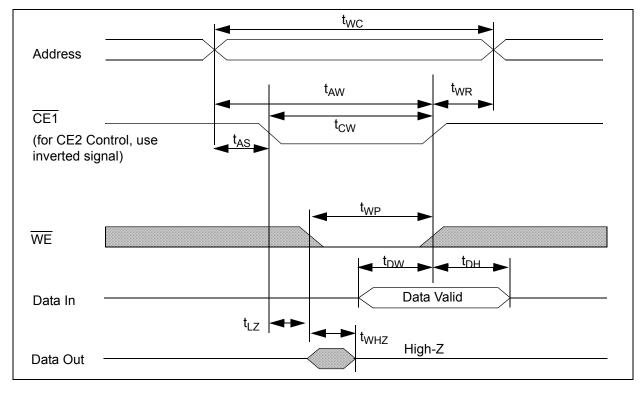
## Timing Waveform of Read Cycle ( $\overline{\text{WE}}$ =V<sub>IH</sub>)



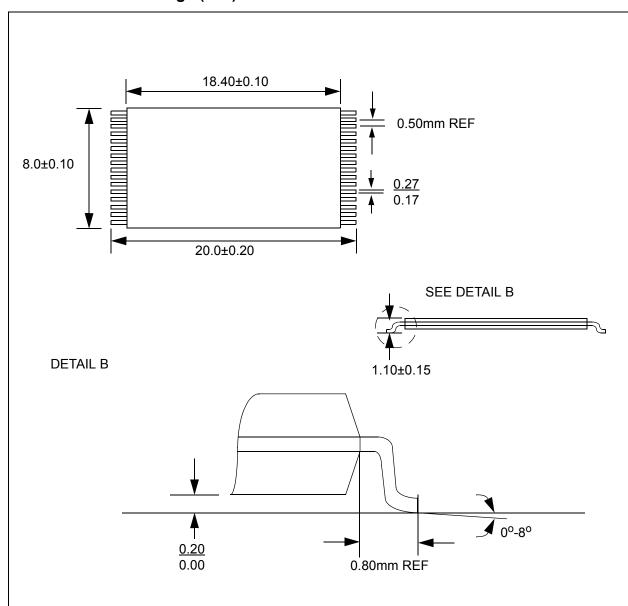
## Timing Waveform of Write Cycle (WE control)



### Timing Waveform of Write Cycle (CE1 Control)



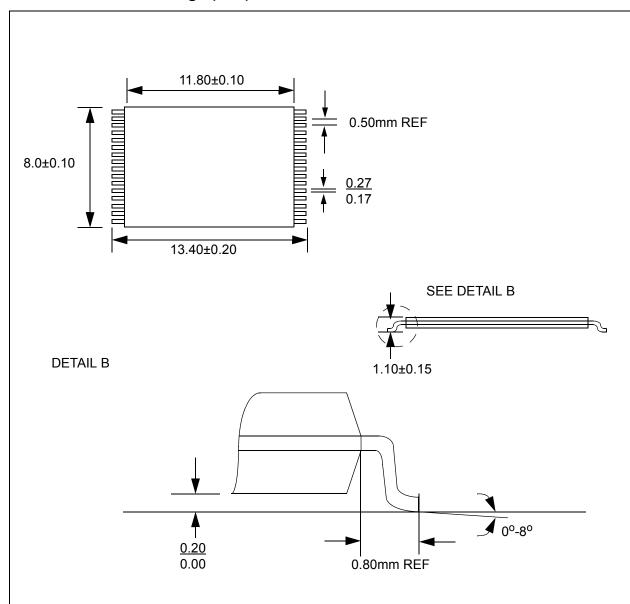
## 32-Lead TSOP-I Package (T32)



#### Note:

- 1. All dimensions in millimeters
- 2. Package dimensions exclude molding flash

### 32-Lead STSOP-I Package (N32)



#### Note:

- 1. All dimensions in millimeters
- 2. Package dimensions exclude molding flash

### **Ordering Information**

Part Number	Package	Shipping Method
N02L83W2AT5I	Leaded 32-TSOP I	Tray
N02L83W2AT25I	Green 32-TSOP I (RoHS Compliant)	Tray
N02L83W2AN5I	N5I Leaded 32-sTSOP I	
N02L83W2AN25I	Green 32-sTSOP I (RoHS Compliant)	Tray
N02L83W2AT5IT	N02L83W2AT5IT Leaded 32-TSOP I	
N02L83W2AT25IT	Green 32-TSOP I (RoHS Compliant)	Tape & Reel
N02L83W2AN5IT Leaded 32-sTSOP I		Tape & Reel
N02L83W2AN25IT	Green 32-sTSOP I (RoHS Compliant)	Tape & Reel

#### **Revision History**

Revision #	Date	Change Description
Α	Jan 2001	Initial Advance Release
В	Mar 2001	Added Table 3: Capacitance Revised quiescent operating current, changed pin 31 to CE1, modified table 1 and figure 2, other minor edits
С	Dec. 2001	Part number change from EM256L08, modified Overview and Features, added Page Mode Operation diagram and Package diagram, revised Operating Characteristics table, Functional Description table, Timing diagrams, and Ordering Information diagram
D	Nov. 2002	Replaced Isb and Icc on Product Family table with typical values
E	Oct. 2004	Added Green Package Option
F	Dec. 2005	RoHS Compliant added onto Green packages
G	September 2006	Converted to AMI Semiconductor
8	July 2008	Converted to ON Semiconductor and new part numbers

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